


<b>Search Notes</b>  	<b>Application/Control No.</b>  10719192	<b>Applicant(s)/Patent Under Reexamination</b>  BAEK ET AL.
	<b>Examiner</b>  Tu, Julia P	<b>Art Unit</b>  2611

SEARCHED			
Class	Subclass	Date	Examiner
375	260,229,316,354	5/20/2010	L.M.
370	310,324,395.62,503	5/20/2010	L.M.
708	404	5/20/2010	L.M.

SEARCH NOTES		
Search Notes	Date	Examiner
EAST, IEEE, Inventor Name Search, Consulted M. Ghayour, Consulted K. Harper	5/20/2010	L.M.

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
375	229,316,354	5/20/2010	L.M.
370	310,324,395.62,503	5/20/2010	L.M.
708	404	5/20/2010	L.M.

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